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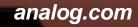
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RELIABILITY REPORT

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RELIABILITY DATA LTC5100 / LTC2240 / 2241 / 2242					
8/21/2006					
• OPERATING LIFE TES	Г				
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
QFN/DFN	234 234	0408	0626	234.00 234.00	0 0
HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICF HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
QFN/DFN	50 50	0408	0408	168.00 168.00	0 0
PRESSURE COOKER TEST AT 15 PSIG, +121°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
QFN/DFN	252 252	0313	0633	84.82 84.82	0 0
• TEMP CYCLE FROM -65°C to +150°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
QFN/DFN	279 279	0321	0544	241.11 241.11	0 0
• THERMAL SHOCK FROM -65°C to +150°C					
PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
QFN/DFN	281 281	0313	0544	242.50 242.50	0 0
 (1) Assumes Activation Energy = 0.7 Electron Volts (2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 50.58 FITS (3) Mean Time Between Failures in Years = 2,255 (4) Assumes 20X Acceleration from 85°C to +131°C Note: 1 FIT = 1 Failure in One Billion Hours. 					

Form: 00-03-6209B. R492

Rev 4